

## Supporting Information for

### Manipulating Protons and Oxygen Vacancies in Nickelate Oxides by Thermochemical Dehydration

Haowen Chen<sup>a,b,†</sup>, Zihan Xu<sup>a,b,‡</sup>, Luhan Wei<sup>b</sup>, Mingdong Dong<sup>c</sup>, Yang Hu<sup>b</sup>, Ying Lu<sup>b</sup>, Nian Zhang<sup>d</sup>, Jie Wu<sup>c</sup>, and Qiyang Lu<sup>b,e,\*</sup>

<sup>a</sup> Zhejiang University, Hangzhou 310027, China

<sup>b</sup> School of Engineering, Westlake University, Hangzhou 310030, China

<sup>c</sup> Key Laboratory for Quantum Materials of Zhejiang Province, School of Science, Westlake University, Hangzhou 310030, China

<sup>d</sup> Shanghai Synchrotron Radiation Facility, Shanghai Advanced Research Institute, Chinese Academy of Sciences, Shanghai 201204, China

<sup>e</sup> Research Center for Industries of the Future, Westlake University, Hangzhou 310030, Zhejiang, China

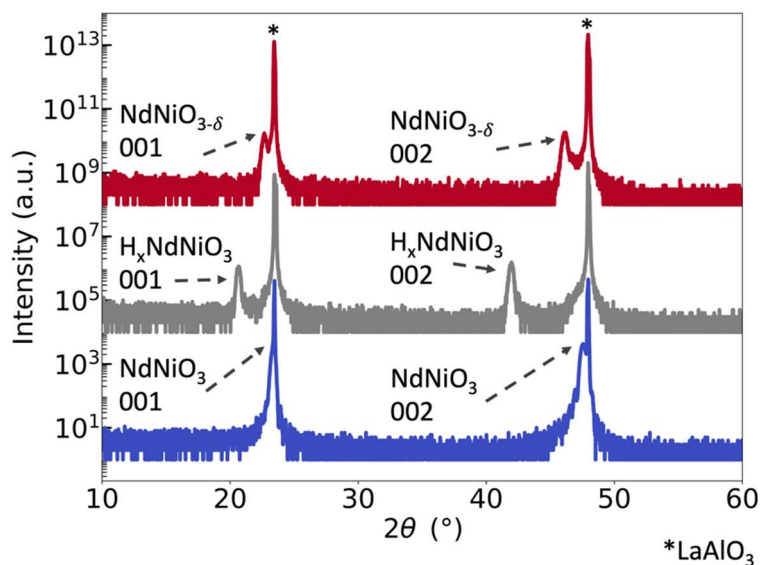
† Electronic supplementary information (ESI) available.

‡ These authors contributed equally to this work.

\*Corresponding author: luqiyang@westlake.edu.cn

## Structural characterizations of pristine $\text{NdNiO}_3$ , protonated $\text{H}_x\text{NdNiO}_3$ , and oxygen deficient $\text{NdNiO}_{3-\delta}$

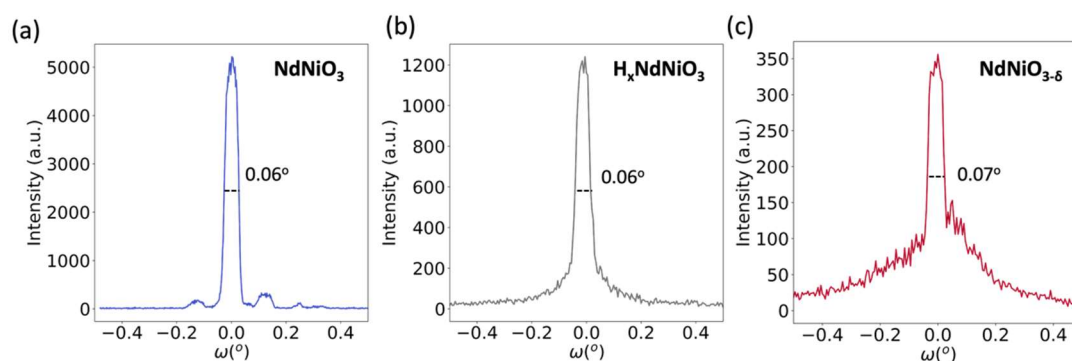
$2\theta$ - $\omega$  scans of the (001) diffraction peak and the (002) diffraction peak of the pristine  $\text{NdNiO}_3$  (denoted as NNO), protonated  $\text{H}_x\text{NdNiO}_3$  (denoted as H-NNO), oxygen deficient  $\text{NdNiO}_{3-\delta}$  are shown in Figure S1.



**Figure S1.** X-ray diffraction (XRD)  $2\theta$ - $\omega$  patterns of NNO, H-NNO, NNO- $\delta$  thin films grown on  $\text{LaAlO}_3$  substrates in the  $2\theta$  range of  $10^\circ$ - $60^\circ$ .

## X-ray diffraction rocking curves of NNO, H-NNO and NNO- $\delta$

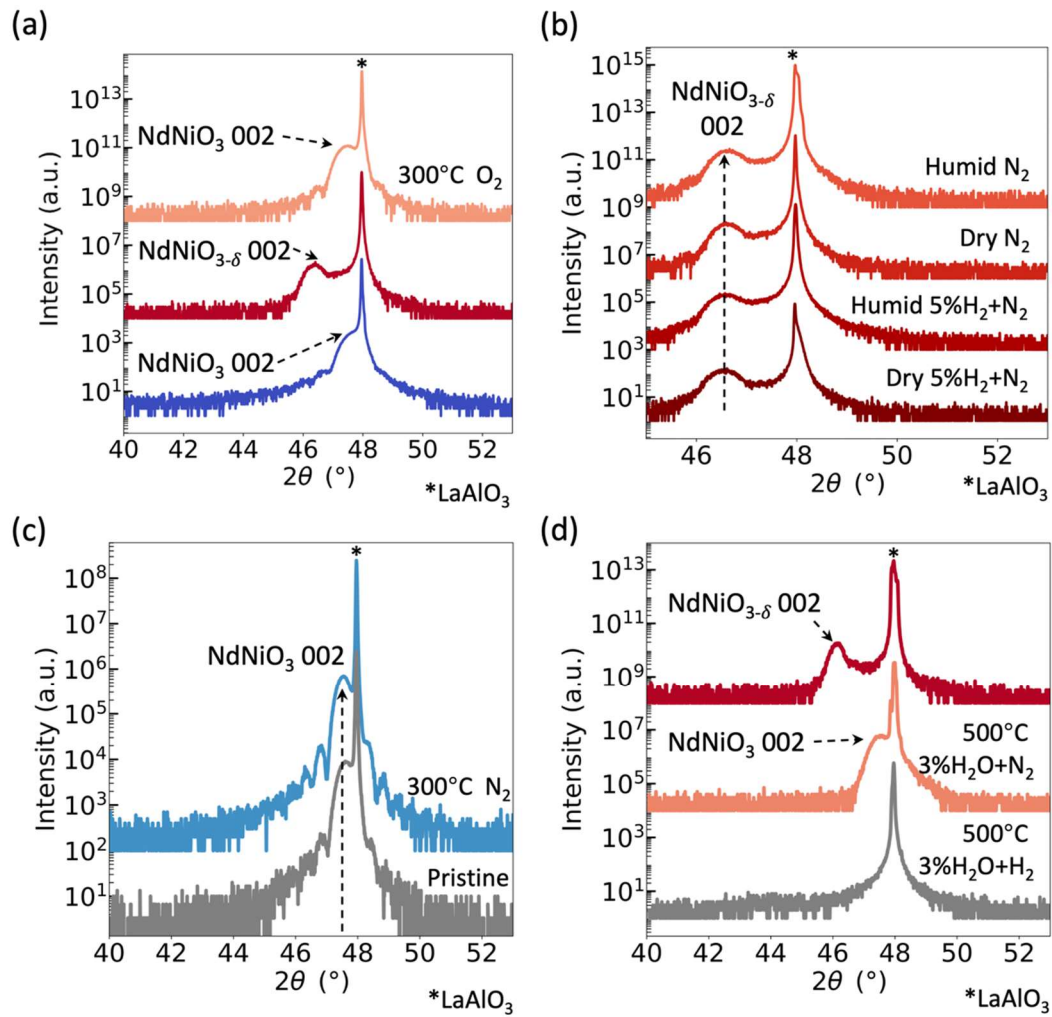
The full-width half maximum (FWHM) of pristine NNO is  $\sim 0.06^\circ$  (Figure S2a). Figure S2b&c shows the FWHM of rocking curves of protonated H-NNO and oxygen deficient NNO- $\delta$  is roughly the same, which is comparable with the pristine NNO. The narrow width of rocking curves of the latter two samples indicates that they have equally good crystal quality.



**Figure S2.** (a) The rocking curve of the NNO thin film, (b) The rocking curve of the H-NNO thin film, (c) The rocking curve of the NNO- $\delta$  thin film.

## Structural evolution of NNO- $\delta$ under different conditions

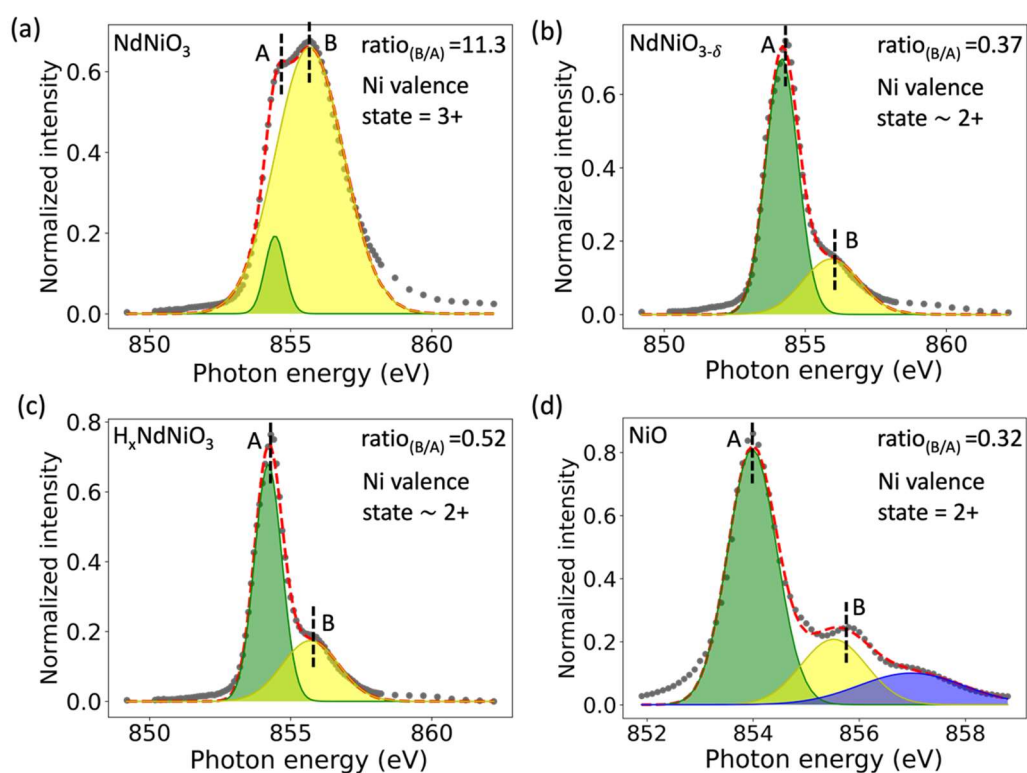
We have characterized the crystal structure of NNO- $\delta$  under different ambient conditions. We first annealed the oxygen deficient sample in a pure O<sub>2</sub> atmosphere at 300°C. We found that the NNO- $\delta$  phase can restore to the pristine NNO without oxygen deficiency, as shown in Figure S3a. We further investigated the dehydration of protonated H-NNO to NNO- $\delta$  under different reducing atmospheres. Figure S3b shows the XRD patterns NNO- $\delta$  forming in different reducing atmospheres. Here, the humid condition refers to an atmosphere containing 3% H<sub>2</sub>O, and the mix of H<sub>2</sub> and N<sub>2</sub> gas has a volume ratio of 5%: 95%. The lattice constant of NNO- $\delta$  recorded as  $c_{pc, NNO-\delta} = 3.92 \text{ \AA}$ , remains consistent across different reducing atmospheric conditions. We also tested the structure of stability of NNO- $\delta$  sample in different reducing atmospheres at temperatures higher than 300°C as shown in Figure S3c.  $2\theta-\omega$  XRD patterns reveal that NNO- $\delta$  undergoes a reversible phase transition back to the NNO phase when exposed to a humid N<sub>2</sub> atmosphere at 500°C. In contrast, the crystal structure of NNO- $\delta$  degrades to an amorphous structure at the same temperature under humid H<sub>2</sub> at 500°C.



**Figure S3.** (a) Structural characterizations of  $\text{NNO}-\delta$  under pure  $\text{O}_2$  atmosphere.  $2\theta$ - $\omega$  XRD patterns of pristine  $\text{NNO}$  (blue),  $\text{NNO}-\delta$  (red),  $\text{NNO}$  after annealing in  $\text{O}_2$  (orange). (b) Structural characterizations of  $\text{NNO}-\delta$  formed in different reducing atmospheres.  $2\theta$ - $\omega$  XRD patterns show the structure of  $\text{NNO}-\delta$  formed at  $300^\circ\text{C}$  in four different reducing atmospheres: humid  $\text{N}_2$ , dry  $\text{N}_2$ , humid mixture of  $\text{H}_2$  and  $\text{N}_2$  and dry mixture of  $\text{H}_2$  and  $\text{N}_2$ . (c) Stability of  $\text{NNO}-\delta$  at high temperature in different reducing atmospheres. The oxygen deficient  $\text{NNO}-\delta$  sample was annealed at  $500^\circ\text{C}$  in humid  $\text{N}_2$  (orange) and humid  $\text{H}_2$  (grey) atmospheres, respectively.

## Fitting of soft X-ray adsorption spectra of NNO, H-NNO, NNO- $\delta$ , NiO

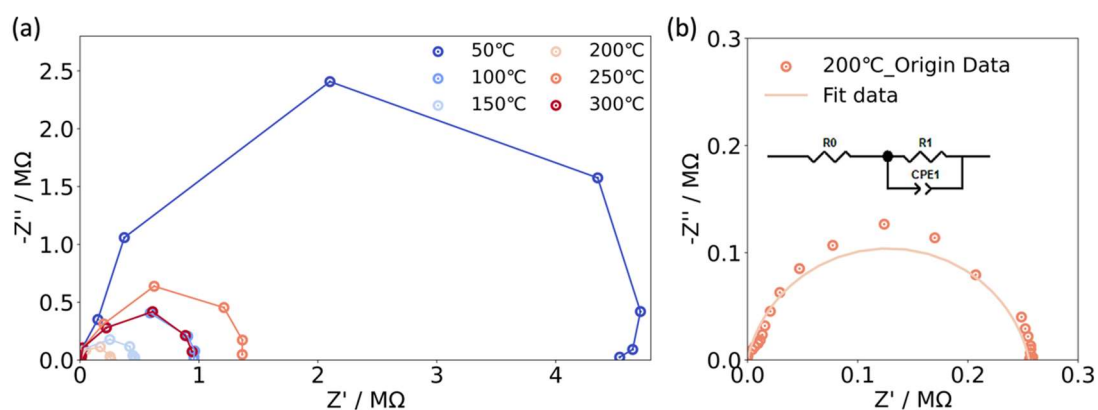
We used two Gaussian peaks for fitting the soft X-ray adsorption spectra (sXAS) of NNO, H-NNO, NNO- $\delta$  and NiO, as shown in Figure S4. Figure S4a shows the two peaks were used for fitting the Ni  $L_3$ -edge sXAS in pristine NNO. The feature peak A is centered at  $\sim 854.5$  eV and the feature peak B is centered at  $\sim 856$  eV. Similar feature peaks are observed in the Ni  $L_3$ -edge of NNO- $\delta$ , H-NNO, and NiO (Figure S4b&c&d). The green Gaussian component represents the feature peak A. The yellow Gaussian component represents the feature peak B. The area ratio compared between feature peak A and feature peak B can be used as a reference to calculate the Ni valence state. The Ni valence state of H-NNO and NNO- $\delta$  is close to  $\text{Ni}^{2+}$  due to their area ration $_{(B/A)}$  is close to the area ration $_{(B/A)}$  of NiO.



**Figure S4.** Fitting results of the Ni  $L_3$ -edge sXAS measured on (a) NNO, (b) NNO- $\delta$ , (c) H-NNO (d) NiO samples.

## Temperature-dependent electrochemical impedance spectroscopy and equivalent circuit analysis

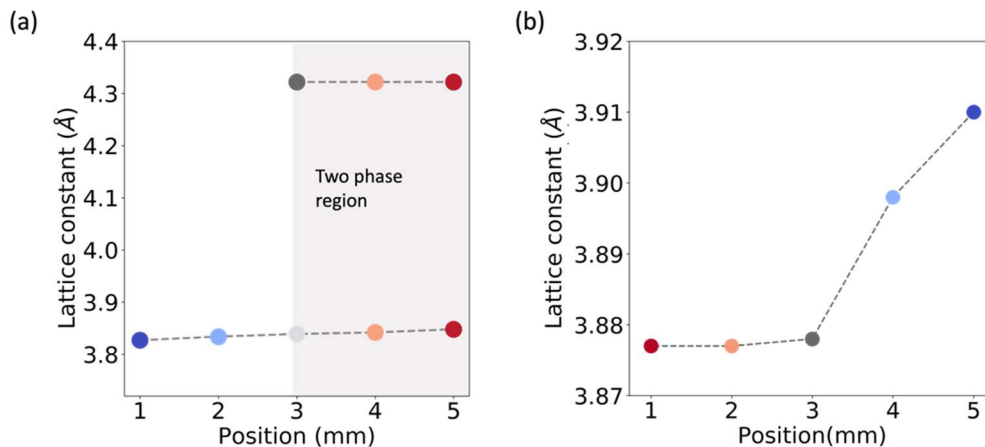
The electrochemical impedance spectroscopy (EIS) was carried out in a humid atmosphere ( $p_{\text{H}_2\text{O}}: p_{\text{N}_2} = 3\%:97\%$ ) while heating the sample from  $50^\circ\text{C}$  to  $300^\circ\text{C}$ . This method allows for the observation of changes in electrical impedance associated with the phase transition from H-NNO to NNO- $\delta$  (Figure S5a). Figure S5b shows the equivalent circuit analysis of the EIS result. The model comprises a resistor ( $R_0$ , which represents the resistance from the wires used for measurements, and/or other sources of contact resistance) in series with a parallel configuration that includes a resistor ( $R_1$ , which represents the resistance of the H-NNO/NNO- $\delta$  thin films) and a constant phase element ( $CPE_1$ , most likely due to the stray capacitance from the wires used).



**Figure S5.** (a) Temperature-dependent Nyquist plots (real part of impedance  $Z' \sim$  imaginary part  $Z''$ ) of the impedance spectra of the phase transition in H-NNO to NNO- $\delta$ . (b) Equivalent circuit modeling for impedance spectra analysis.

## The out-of-plane lattice constant of proton graded H-NNO thin film and oxygen vacancy graded NNO- $\delta$ thin film

We concluded the out-of-plane lattice constant of both H-NNO thin film with proton concentration gradient and NNO- $\delta$  thin film with oxygen vacancy concentration gradient in Figure S6a and Figure S6b, respectively. Figure S6a shows the protonation process happens in two different stages. From 0 mm to 2.5 mm, the proton concentration is low, and the lattice constant of NNO slightly expands from 3.81 Å to 3.84 Å. Once the proton concentration reaches the threshold value, the H-NNO phase with a lattice constant at 4.31 Å forms. From 2.5 mm to 5 mm, a two-phase region exists. Figure S6b shows the dehydration of the graded H-NNO thin film happened in two different stages. From 0 mm to 2.5 mm, dehydration of the NNO phase with low proton concentration induces the oxygen deficient phase NNO- $\delta$  with a lattice constant of  $c_{pc, NNO-\delta} = 3.87$  Å. On the other hand, from 2.5 mm to 5 mm, dehydration of H-NNO with a higher proton concentration resulted in the oxygen deficient phase NNO- $\delta$  with a changing lattice constant  $c_{pc, NNO-\delta}$  between 3.87 Å and 3.91 Å.

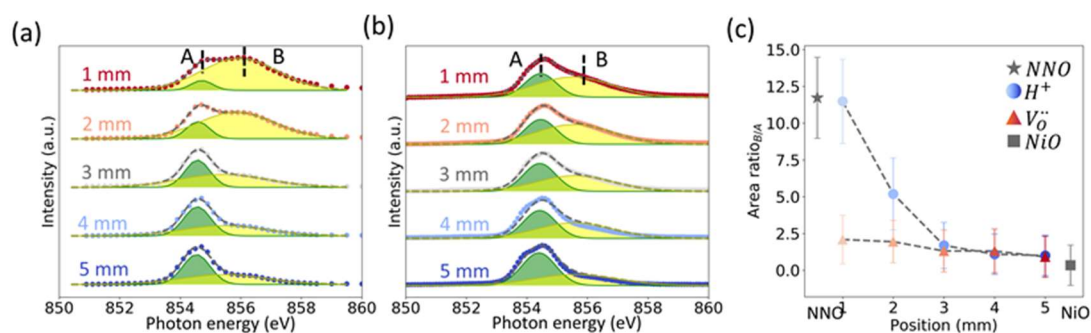


**Figure S6.** (a) The out-of-plane lattice constant of proton concentration gradient thin film extracted from Figure 4a at each spot of the thin film. (b) The out-of-plane lattice constant of oxygen vacancy concentration gradient thin film extracted from Figure 4b at each spot of the thin film.



## Peak fitting results of Ni $L_3$ -edge of proton graded H-NNO thin film and oxygen vacancy graded NNO- $\delta$ thin film

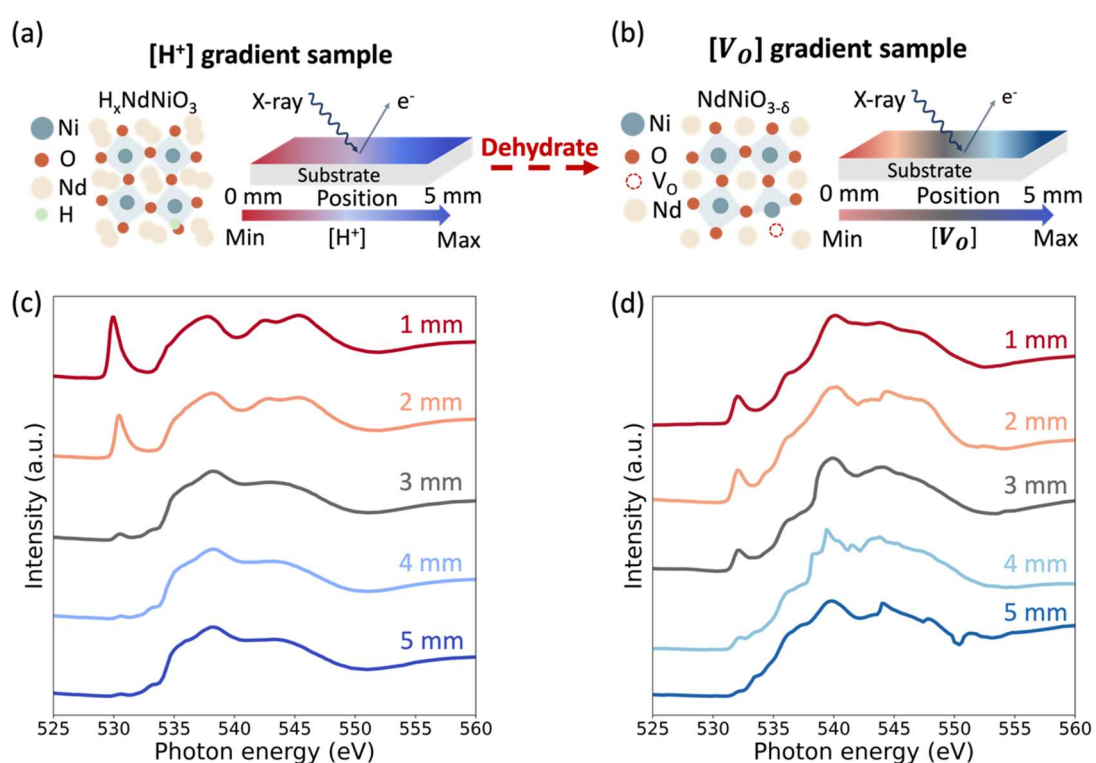
We continuously used two Gaussian peaks to fit the Ni  $L_3$ -edge of H-NNO thin film with proton concentration gradient and NNO- $\delta$  thin film with oxygen vacancy concentration gradient. We concluded the fitting results of the Ni  $L_3$ -edge at different positions of the H-NNO and NNO- $\delta$  thin film in Figure S7a and Figure S7b, respectively. In both Figure S7a&b, the green Gaussian component represents the feature peak A (centered at  $\sim 854.5$  eV) and the yellow Gaussian component represents the feature peak B (centered at  $\sim 856$  eV), which is the same as previous results in Figure S4. We also calculated the area ratio $_{(B/A)}$  of each spot of the H-NNO and NNO- $\delta$  thin film as shown in Figure S7c. Using the area ratio $_{(B/A)}$  of NNO and NiO as a reference, we can calculate the Ni valence state change of both proton graded H-NNO thin film and oxygen vacancy graded NNO- $\delta$  thin film.



**Figure S7.** (a) Peak fitting results of Ni  $L_3$ -edge of H-NNO thin film with a proton concentration gradient. (b) Peak fitting results of Ni  $L_3$ -edge of NNO- $\delta$  thin film with a gradient of oxygen vacancy concentration. (c) Area ratio $_{(B/A)}$  of each spot of the H-NNO and NNO- $\delta$  thin film. The blue gradient spot is the thin film along the proton concentration gradient. The red gradient spot is the thin film along the oxygen vacancy concentration gradient.

## O *K*-edge sXAS of proton graded H-NNO thin film and oxygen vacancy graded NNO- $\delta$ thin film

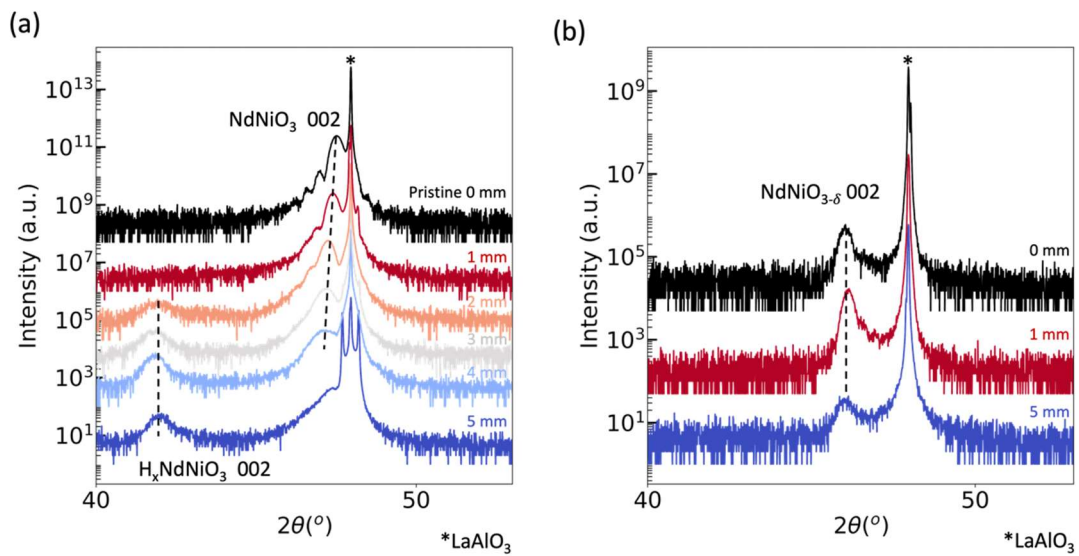
The oxygen vacancy concentration gradient sample was synthesized by annealing the proton gradient sample a in an N<sub>2</sub> atmosphere. The pre-edge peak at 530 eV in both Figure S8a&b represents the hybridization between the Ni 3*d* orbital and the O 2*p* orbital<sup>1</sup>. For both proton defects and oxygen vacancies, the formation of defects induces electron doping, which suppresses the pre-edge peak.



**Figure S8.** (a) Schematic showing sXAS with the spatial resolution to characterize the Ni valence state of the H-NNO thin film. (b) Schematic showing sXAS with the spatial resolution to characterize the Ni valence state of the NNO- $\delta$  thin film. (c) O *K*-edge of the protonated H-NNO thin film sample with the proton concentration gradient. (d) O *K*-edge of the oxygen deficient NNO- $\delta$  thin film sample with oxygen vacancy concentration gradient.

## Structural characterizations of proton graded H-NNO thin film and the same sample after annealing in a pure H<sub>2</sub> atmosphere

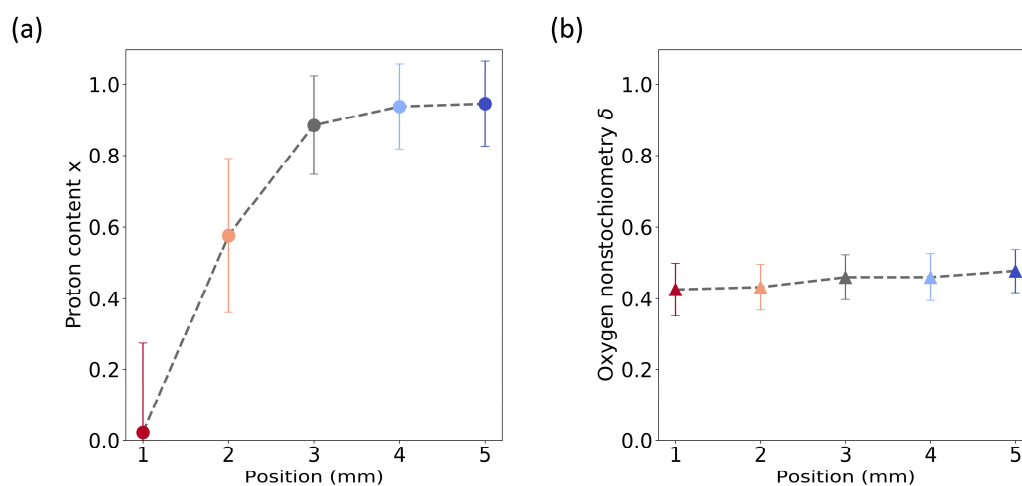
We annealed the H-NNO thin film with proton concentration gradient in a pure H<sub>2</sub> atmosphere at 300°C. The oxygen vacancy concentration in the H<sub>2</sub> annealed sample is homogenous. The lattice constant is  $c_{pc, NNO-\delta} = 3.94 \text{ \AA}$  and remains consistent throughout the entire thin film.



**Figure S9.** (a)  $2\theta$ - $\omega$  XRD patterns of the thin film along the proton concentration gradient. (b)  $2\theta$ - $\omega$  XRD patterns for identical locations on the thin film as specified in a, detailing the diffraction characteristics corresponding to each spot.

## Non-stoichiometry at different position of the concentration gradient thin film

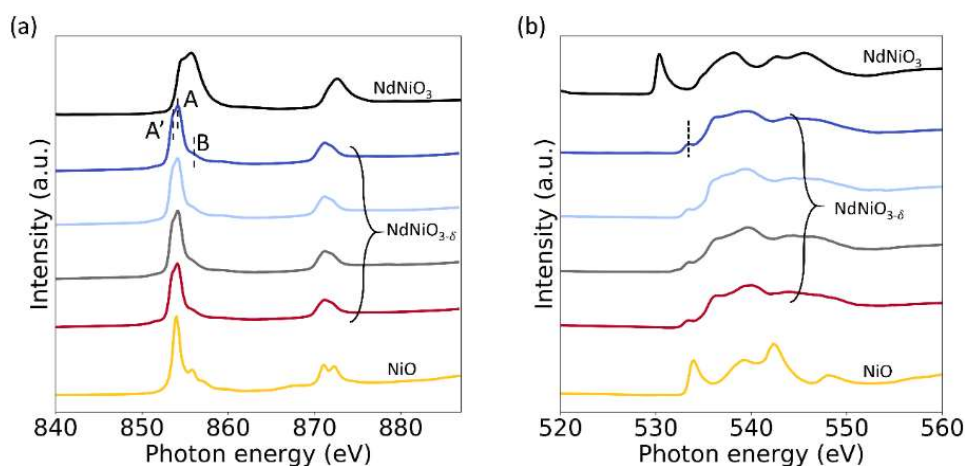
we have plotted the non-stoichiometry (i.e., hydrogen non-stoichiometry  $x$  as in  $H_xNdNiO_3$  and oxygen non-stoichiometry  $\delta$  as in  $NdNiO_{3-\delta}$ ) as a function of lateral position in the samples with a defect concentration gradient. Figure S10a shows the hydrogen non-stoichiometry  $x$  as a function of position in the sample with a proton concentration gradient, while Figure S10b shows the oxygen non-stoichiometry  $\delta$  at different positions in the sample after thermochemical dehydration.



**Figure S10** (a) Hydrogen non-stoichiometry  $x$  at different positions of a  $H_xNdNiO_3$  thin film sample with proton concentration gradient. (b) Oxygen non-stoichiometry  $\delta$  at a different position of a  $NdNiO_{3-\delta}$  thin film sample with oxygen vacancy concentration gradient.

## Ni $L_{2,3}$ -edge and O $K$ -edge sXAS of the hydrogen annealed sample

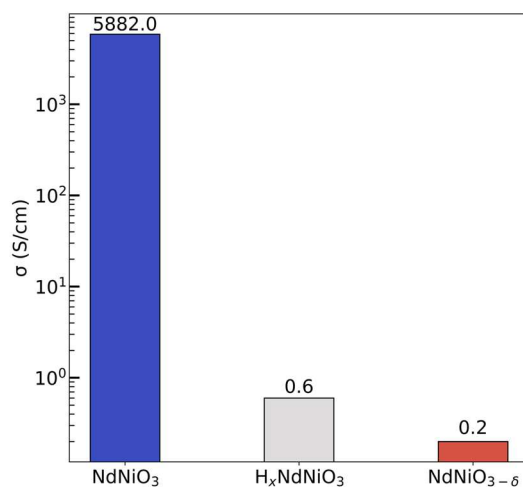
We synthesized the NNO- $\delta$  sample by annealing the sample with the proton concentration gradient in the pure  $H_2$  atmosphere at  $300^\circ\text{C}$ . The oxygen vacancy concentration remained homogenous across the thin film. The extra feature peak A' at 854 eV in Ni  $L_{3}$ -edge of oxygen deficient sample NNO- $\delta$  has been observed (Figure S11a). A similar extra feature peak has also been observed in the infinite layer  $\text{LaNiO}_2$  or  $\text{NdNiO}_2$ <sup>1,2</sup>. A pre-edge peak in the O  $K$ -edge of oxygen deficient NNO- $\delta$  is visible, marked by a dashed line in Figure S10b. A similar pre-edge peak has been observed in  $\text{Nd}_{0.8}\text{Sr}_{0.2}\text{NiO}_2$ <sup>2</sup>,  $\text{Nd}_4\text{Ni}_3\text{O}_8$ <sup>3</sup> and  $\text{Nd}_6\text{Ni}_5\text{O}_{12}$ <sup>4</sup>. The sXAS results indicate that the Ni valence state of the hydrogen annealed sample is mixed  $\text{Ni}^+/\text{Ni}^{2+}$ .



**Figure S11.** The sXAS of NNO- $\delta$  (a) Ni  $L_{2,3}$ -edge and (b) O  $K$ -edge.

## The room-temperature conductivity of pristine $\text{NdNiO}_3$ , protonated $\text{H}_x\text{NdNiO}_3$ and oxygen deficient $\text{NdNiO}_{3-\delta}$

As shown in Figure S12, it is the comparison between the room-temperature conductivity of  $\text{NdNiO}_3$  samples with protons/oxygen vacancies and a pristine  $\text{NdNiO}_3$  sample. We can see that the conductivity of  $\text{NdNiO}_3$  samples with defects (either protons or oxygen vacancies) are orders of magnitude lower than that of the pristine  $\text{NdNiO}_3$  sample.



**Figure S12.** The room-temperature conductivity of pristine  $\text{NdNiO}_3$ , protonated  $\text{H}_x\text{NdNiO}_3$ , and oxygen deficient  $\text{NdNiO}_{3-\delta}$ .

## References

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